ARTS hpUltra 3000

RELIABILITY TEST SYSTEM FOR AI & HPC

POWER
PRECISION
RELIABILITY

84x3kW Test Sites

Up to **64** Independent Power Supplies per DUT

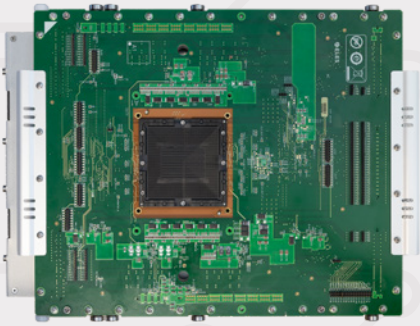
ELES

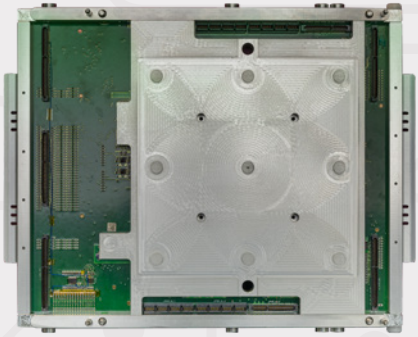
ART hpUltra 3000

- **From “Pass/Fail” to “Learning from Fail”:** Integrating combined stress and in-situ testing for advanced reliability test.
- **Smart Stressing:** Automated ICs equivalent lifetime calculation tailored for single-device stress optimization.
- **Scalable Architecture enabling Adaptive Test:** Independent tester resources per DUT, including 64 device power supplies, for extreme flexibility, maximum throughput and yield.
- True 84 sites per system up to 3kW each
- Fully configurable current per voltage domain
- 2-phases liquid cooling technology for very high power density > 150W/sqcm
- Liquid cooled on-board electronics

FIXTURES

FIXTURES FOR Q&R AND MANUFACTURING ENVIRONMENT





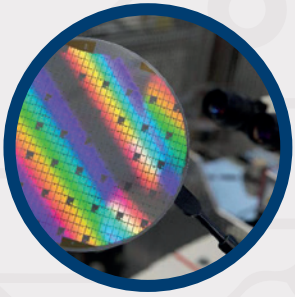
- Consolidated design rules and qualified building blocks to optimize Fixtures performances and reliability.
- Qualified components libraries and application of consolidated Design for Manufacturing rules.
- BoST IPs to Maximize test and stress coverage, including high accuracy parametric measurament for an effective Test for Reliability (TfR) flow.
- Fixture Robustness optimized for extreme conditions and continuous handling.
- Signal and Power Integrity simulation / optimization service to guarantee and optimize electrical performance versus test application specs.
- Thermal Simulation to Guarantee Stress Temperature accuracy at extreme conditions.

RETE
RELIABILITY EMBEDDED TEST ENGINEERING

UNIQUE SELLING PROPOSITION

state-of-the-art test and reliability flow, that ensures:

Early Detection of issues in the Design Process



Shorten Time to Market and CoO minimization

Zero defect and zero scraps Production

... moving from a Pass-Fail to Learn From Fail approach

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